

<b>FORM PTO-1449</b> <b>INFORMATION DISCLOSURE STATEMENT</b>		DOCKET NUMBER 102155-200		SERIAL NUMBER <del>N/A</del> <b>10/017,863</b>		
		APPLICANT Szuchain F. Chen, et al.				
		FILING DATE <del>N/A</del> <b>12/12/01</b>		GROUP ART UNIT <b>1775</b>		
U.S. PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPR.
<b>RRK</b>	3,193,484	07/06/65	Gleim	204	79	
<b>RRK</b>	3,666,637	05/30/72	MacKay	204	30	
<b>RRK</b>	4,234,395	11/18/80	Berdan et al.	204	12	
<b>RRK</b>	4,323,632	04/06/82	Berdan et al.	428	626	
<b>RRK</b>	4,952,531	08/28/90	Cherukuri	501	69	
<b>RRK</b>	5,022,968	06/11/91	Lin et al.	204	28	
<b>RRK</b>	5,098,796	03/24/92	Lin et al.	428	607	
<b>RRK</b>	5,230,932	07/27/93	Chen et al.	428	607	
<b>RRK</b>	5,250,363	10/05/93	Chen	428	607	
<b>RRK</b>	5,449,951	09/12/95	Parthasarathi et al.	257	677	
<b>RRK</b>	5,573,845	11/12/96	Parthasarathi et al.	428	306.6	
<b>RRK</b>	5,658,869	08/19/97	Singer	510	272	
FOREIGN PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION	
					YES	NO
OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)						
<b>RRK</b>	"Metallization Contamination," Microelectronic Defects Database, CALCE Electronic Products and Systems Center, University of Maryland, April 12, 2000.					
<b>RRK</b>	Barnes and Robinson, "The Impact of Ionic Impurities in Die Attach Adhesives on Device Performance", Proc. Of 34 <sup>th</sup> Electronics Components Conf., May, 1984, p. 68					
EXAMINER: <b>Robert R. Koehler</b>				DATE CONSIDERED: <b>February 22, 2004</b>		

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U.S. PATENT DOCUMENTS						
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FOREIGN PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION	
					YES	NO
OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)						
<b>RRK</b>	Lee, C., et al., "An Analytical Characterization and Reliability Testing of an Adhesion Enhancing Zn-Cr Leadframe Coating for Popcorn Prevention", Conference Preprint, 1998, 9 pages.					
EXAMINER: <b>Robert R. Koehler</b>				DATE CONSIDERED: <b>February 22, 2004</b>		

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U.S. PATENT DOCUMENTS						
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FOREIGN PATENT DOCUMENTS						
EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	TRANSLATION	
					YES	NO
RRK	JP 55-44536	3/1980	Japan	C21D 9/48	Abs.	X
OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)						
RRK	International Search Report for PCT/US01/50660, filing date December 20, 2001					
EXAMINER: Robert R. Koehle				DATE CONSIDERED: February 22, 2004		

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